

Notice of References Cited	Application/Control No. 10/780,306		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Deandra M. Hughes		Art Unit 3663	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,819,814	11-2004	Forrest et al.	385/14
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	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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